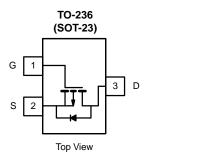
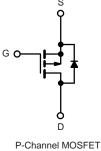


P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω) Typ.	I _D (A) ^a	Q _g (Typ.)			
	0.046 at V _{GS} = - 10 V	- 5.6				
- 30	0.049 at V _{GS} = - 6 V	- 5	11.4 nC			
	0.054 at V _{GS} = - 4.5 V	-4.5				





FEATURES

- TrenchFET[®] Power MOSFET
- 100 % R_g Tested

APPLICATIONS

- For Mobile Computing
 - Load Switch - Notebook Adaptor Switch
 - DC/DC Converter



Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	- 30	N	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		- 5.6		
Constinuous Drain Current (T. 450 °C)	T _C = 70 °C		- 5.1		
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _A = 25 °C		- 5.4 ^{b,c}		
	T _A = 70 °C		- 4.3 ^{b,c}	А	
Pulsed Drain Current (t = 100 µs)		I _{DM}	- 18		
	T _C = 25 °C		- 2.1		
Continous Source-Drain Diode Current	T _A = 25 °C	I _S	- 1 ^{b,c}		
	T _C = 25 °C		2.5		
Mauinum Daura Diasis atian	T _C = 70 °C		1.6	10/	
Maximum Power Dissipation	T _A = 25 °C	P _D	1.25 ^{b,c}	W	
	T _A = 70 °C	1 -	0.8 ^{b,c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS

Parameter			Maximum	Unit		
t ≤ 5 s	R _{thJA}	75	100	°C/W		
Steady State	R _{thJF}	40	50	C/W		
			$t \le 5 \text{ s}$ R_{thJA} 75	t \leq 5 s R _{thJA} 75 100		

Notes:

a. Based on T_C = 25 °C.
b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static					•	1
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 250.04		- 19		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	- 0.5		- 2.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μA
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 V$, $V_{GS} = -10 V$	- 2.5			A
		V _{GS} =- 10 V, I _D = - 4.4 A		0.046	0.055	Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} =- 6 V, I _D = - 4 A		0.049	0.058	
		V _{GS} =- 4.5 V, I _D = - 3.6 A			0.063	-
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 3.4 A		18		S
Dynamic ^b		· ·· ·		ł	l	<u> </u>
Input Capacitance	C _{iss}			1295		1
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		150		pF
Reverse Transfer Capacitance	C _{rss}			130		
		V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 5.4 A		24	36	
Total Gate Charge	Qg			11.4	17	nC
Gate-Source Charge	Q _{gs}	V _{DS} = - 15 V, V _{GS} = - 4.5 V, I _D = - 5.4 A		3.4		
Gate-Drain Charge	Q _{gd}			3.8		
Gate Resistance	Rg	f = 1 MHz	1.5	7.7	15.4	Ω
Turn-On Delay Time	t _{d(on)}		-	13	20	
Rise Time	t _r	V _{DD} = - 15 V, R _I = 3.5 Ω		4	8	- - - ns -
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -4.3 \text{ A}, \text{ V}_{\text{GEN}} = -10 \text{ V}, \text{ R}_{\text{a}} = 1 \Omega$		38	57	
Fall Time	t _f			6	12	
Turn-On Delay Time	t _{d(on)}			28	42	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, \text{ R}_1 = 3.5 \Omega$		16	24	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -4.3 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_q = 1 \Omega$		30	45	
Fall Time	t _f			10	20	
Drain-Source Body Diode Characteristic				10	20	
Continuous Source-Drain Diode Current I_S $T_C = 25 °C$		T _C = 25 °C			- 2.1	
Pulse Diode Forward Current ($t = 100 \mu s$)	I _{SM}	Ŭ U			- 80	A
Body Diode Voltage	V _{SD}	I _S = - 4.3 A, V _{GS} = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}	<u> </u>		15	23	ns
Body Diode Reverse Recovery Time 4, Body Diode Reverse Recovery Charge Q		•		7	14	nC
Reverse Recovery Fall Time	t _a	I _F = - 4.3 A, dl/dt = 100 A/μs, T _J = 25 °C		8	17	
Reverse Recovery Rise Time	t _b	<u> </u>		7	}	ns

Notes:

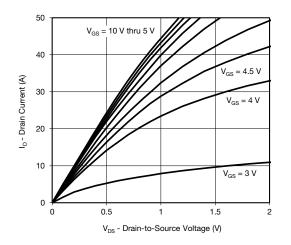
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

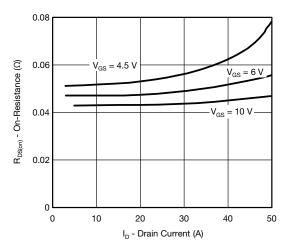
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

semi

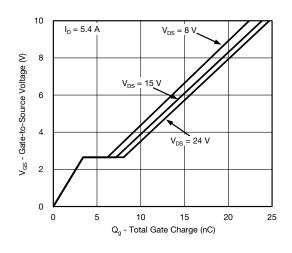




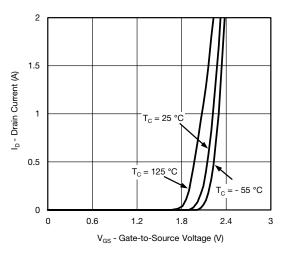
Output Characteristics



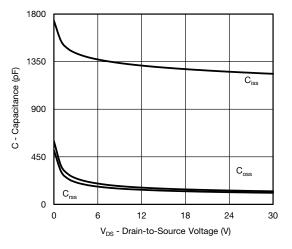
On-Resistance vs. Drain Current



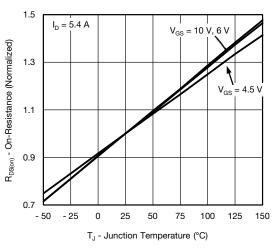
Gate Charge



Transfer Characteristics

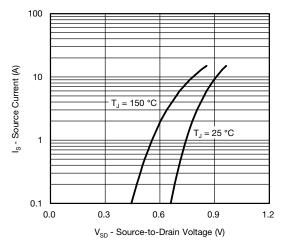




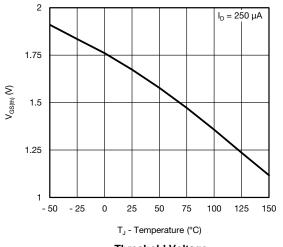


On-Resistance vs. Junction Temperature

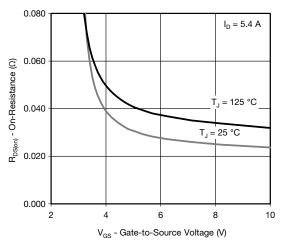




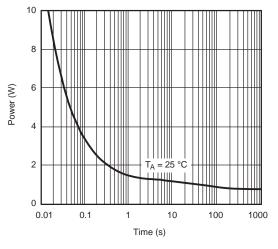
Source-Drain Diode Forward Voltage



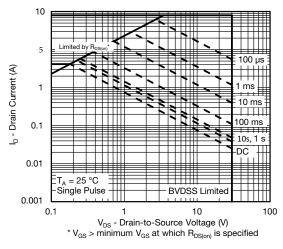
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

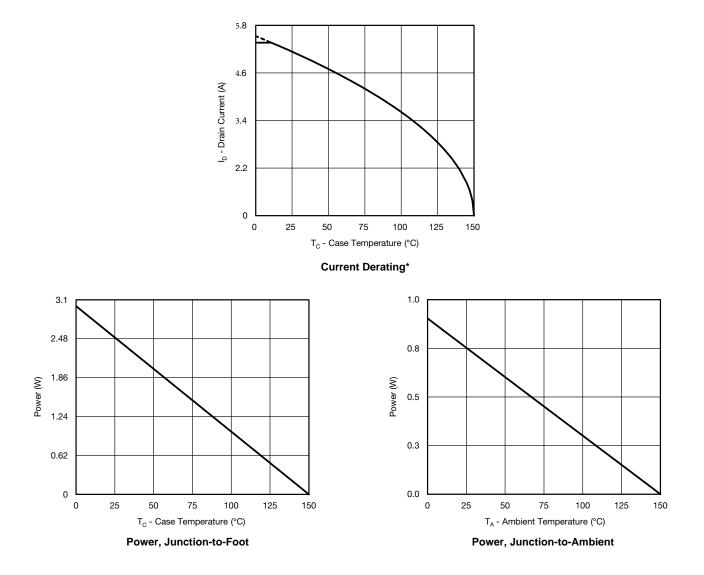


Single Pulse Power (Junction-to-Ambient)



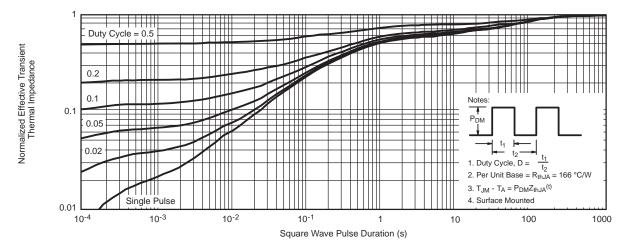
Safe Operating Area, Junction-to-Ambient



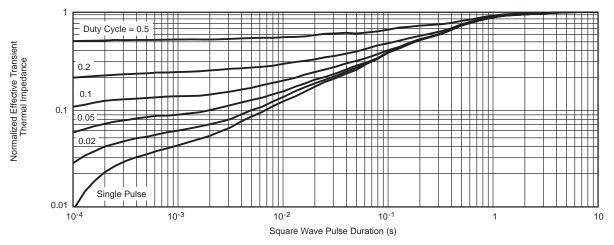


* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





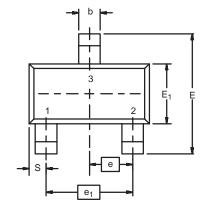
Normalized Thermal Transient Impedance, Junction-to-Ambient

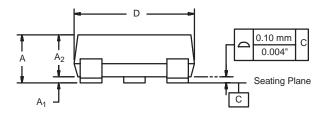


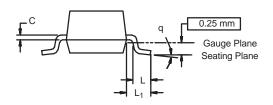
Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-23 (TO-236): 3-LEAD



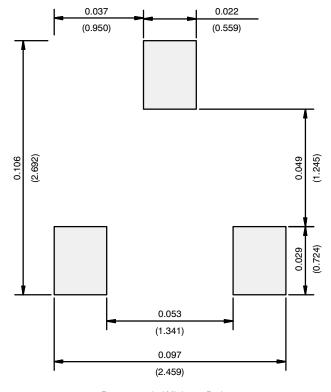




Dim	MILLIN	IETERS	INCHES		
	Min	Мах	Min	Max	
Α	0.89	1.12	0.035	0.044	
A ₁	0.01	0.10	0.0004	0.004	
A ₂	0.88	1.02	0.0346	0.040	
b	0.35	0.50	0.014	0.020	
С	0.085	0.18	0.003	0.007	
D	2.80	3.04	0.110	0.120	
E	2.10	2.64	0.083	0.104	
E ₁	1.20	1.40	0.047	0.055	
е	0.95 BSC		0.0374 Ref		
e ₁	1.90 BSC		0.0748 Ref		
L	0.40	0.60	0.016	0.024	
L ₁	0.64 Ref		0.025 Ref		
S	0.50 Ref		0.020 Ref		
q	3°	8°	3°	8°	
ECN: S-03946-Rev. K, 09- DWG: 5479	Jul-01	•			



RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads Dimensions in Inches/(mm)



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